

Short Bunch Beam Profiling

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Abstract

The complete longitudinal profiling of short electron bunches is discussed in the context of 4th generation light sources. The high peak current required for the SASE lasing process is achieved by longitudinal compression of the electron bunch. The lasing process also depends on the preservation of the transverse emittance along the bunch during this manipulation in longitudinal phase space. Beam diagnostic instrumentation needs to meet several challenges: The bunch length and longitudinal profile should be measured on a single bunch to characterize the instantaneous, peak current along the bunch. Secondly, the transverse emittance and longitudinal energy spread should be measured for slices of charge along the bunch. Several techniques for invasive and noninvasive bunch profiling will be reviewed, using as examples recent measurements from the SLAC Sub Picosecond Photon Source (SPPS) and the planned diagnostics for the Linac Coherent Light Source (LCLS). These include transverse RF deflecting cavities for temporal streaking of the electron bunch, RF zero-phasing techniques for energy correlation measurements, and electro-optic measurements of the wake-field profile of the bunch.

Paper not received

(See slides of talk on
following pages)




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 for Particle Accelerators
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SHORT BUNCH BEAM PROFILING

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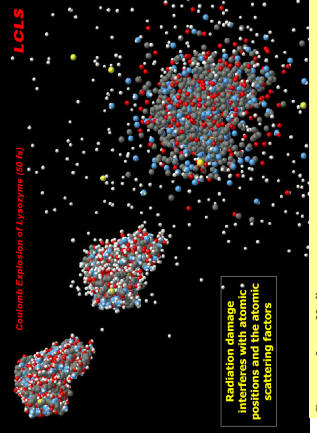
Introduction

Motivation for short bunches in 4th generation light sources (LCLS, TTF2 ...)

- Self Amplified Spontaneous Emission (SASE) requires high charge density to reach saturation
 - Gain length reduced with higher peak current
- Experimenters seek the highest temporal resolution for stroboscopic images of molecular reactions
 - The short, ultra-bright SASE radiation pulse destroys the molecule but image can be retrieved if it was taken quickly enough

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LCLS



Radiation damage interfaces with atomic positions and the atomic scattering factors

Courtesy Janos Hajdu, *Structural Studies on Single Particles and Biomolecules for LCLS*

... Introduction

Short bunches also finding applications in High Energy-Density beam experiments

- Plasma-wakefield experiment E164 at SLAC
- Beam-plasma interaction scales as $1/\sigma_z^2$
- Laboratory astrophysics experiments
 - Utilize the extreme peak fields associated with the high peak current in a short bunch
- Beam-matter interactions

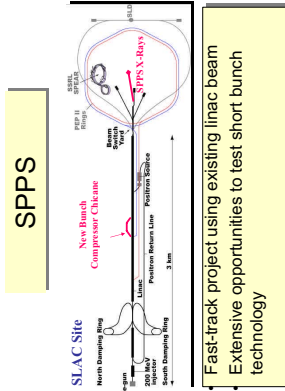
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Short Bunches at SLAC

- The Linac Coherent Light Source, LCLS
 - An X-Ray FEL starting construction ~2005
- The Sub Picosecond Particle Source, SPPS
 - A bunch compression scheme in the existing linac
 - Experiments with short electron bunches
 - And short-pulse spontaneous X-Rays from an undulator **at bremsstrahlung**
- Many laboratories around the world are contributing to progress in this burgeoning field

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SPPS



Fast-track project using existing linac beam

Extensive opportunities to test short bunch technology

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Bunch Length Profiling Techniques

- Transverse RF deflecting cavity
 - Setup and measurements
- Electro Optic techniques
 - limits to resolution for extremely short bunches
 - Chirp, or induced correlated energy spread
 - Transforms bunch length into energy spread
- Relative measurement techniques
 - Wakefield energy loss scan
 - Measurement of CSR power spectral density
 - Measurement of THz radiation from wakefields as GDR
 - Auto correlation of COTR using interferometry

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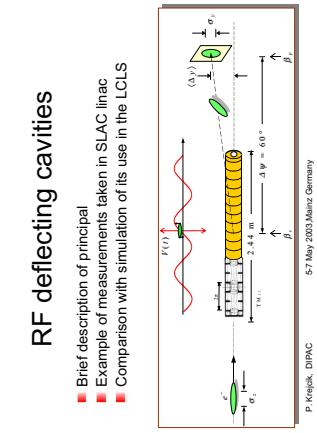
Review of Techniques

- Quantifying σ_z
 - Both relative and absolute measurements
- Bunch length charge distribution
 - Slicing up the bunch and measuring along the bunch
 - Energy spread, transverse emittance
- Relevant because FEL SASE depends on local parameters of slice that is being sliced

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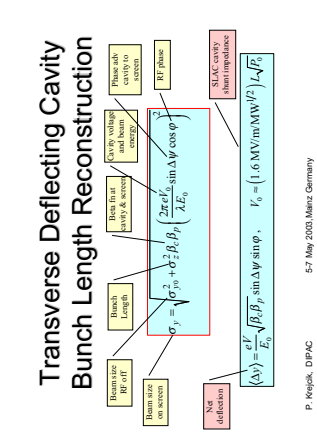
RF deflecting cavities

- Brief description of principal
- Example of measurements taken in SLAC linac
- Comparison with simulation of its use in the LCLS



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Transverse Deflecting Cavity Bunch Length Reconstruction



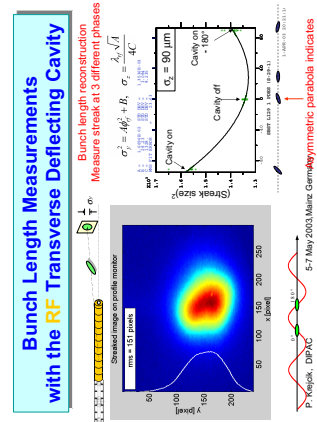
$\sigma_z = \frac{eV}{E_0} \sqrt{\beta_x \beta_y} \sin \Delta\varphi \sin \varphi$

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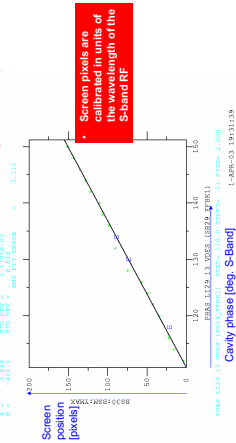
Bunch Length Measurements with the RF Transverse Deflecting Cavity



Streaked image of possible monitor
 Bunch length reconstruction
 Measure streak at 3 different phases
 $\sigma_z^2 = 4\beta_x^2 + \beta_y$, $\sigma_z = \sqrt{4\beta_x^2 + \beta_y}$

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**Calibration scan for RF
transverse deflecting cavity**



Slice Emittance Measurements in Conjunction With RF Deflector Bunch Length Measurement

— Simulations of LCLS Beam From P. Emma

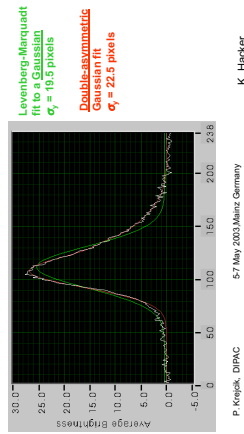
X-Y projection of beam
On Sect 2 profile monitor
RF deflector OFF

X-Y projection of beam
On Sect 2 profile monitor
RF deflector ON

... In combination with quad scan gives SLICE X-EMITTANCE

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Fitted width to streaked, vertical beam size:



Slice Energy Spread Measurements in Conjunction With RF Deflector Bunch Length Measurement

— Simulations of LCLS Beam From P. Emma

Longitudinal phase space at end of linac
... gives SLICE ENERGY SPREAD

XY profile monitoring of "streaked" beam at high dispersion location in BL2

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Zero Phase Crossing Measurement of Bunch Length

— LCLS Simulation From P. Emma, Using ELEGANT (M. Borland)

Energy distribution

Longitudinal phase space

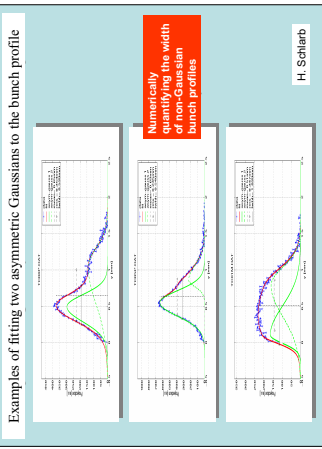
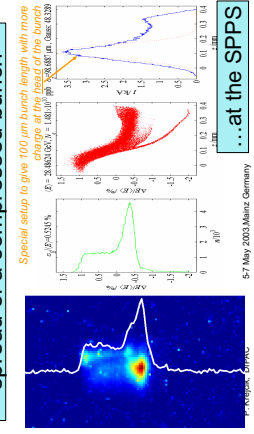
Horizontal distribution at high η

... Relative coordinate of bunch in energy coordinate
... gives energy spread at high dispersion location

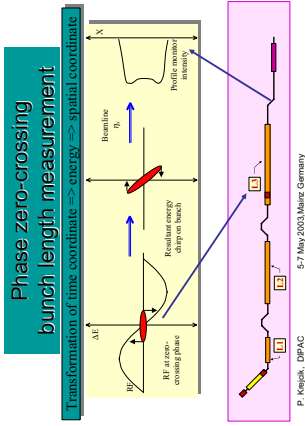
$$\sigma_x = \frac{1}{\sqrt{2}} \sqrt{\frac{E}{\eta} \left(\sigma_x^2 + \sigma_\delta^2 + \sigma_{\delta'}^2 \right)}$$

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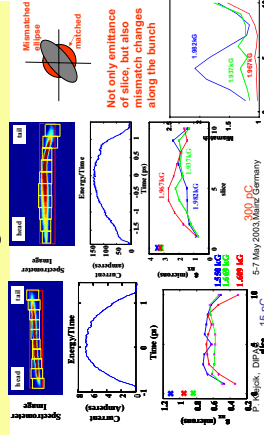
Measured and predicted energy spread of a compressed bunch



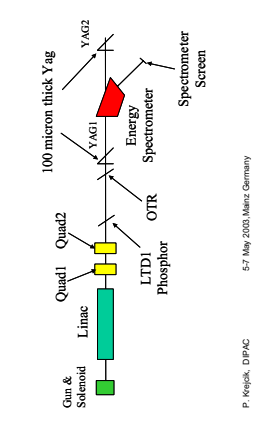
We can also use the longitudinal RF to measure properties of SLICES along the bunch...



Slice emittances for 15 pC and 300 pC bunch charges



Slice emittance and energy spread measurement at the SLAC GTF — Dowell et al



Principal of Electro Optic Detection

Electro-optic detection based on the transmission of chirped laser pulses

EO Crystal Analyzer Spectrometer

Initial laser chip Box charge Gated spectral signal

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Electro Optic resolution limits for extremely short bunches

- Bandwidth limited by probe laser pulse to ~5 fs
- EO effect is ~2 fs
- Moving the problem from electron bunch measurement over to measuring a photon pulse
- Different transformations exist to measure photons
- Temporal to frequency domain transformation with chirped laser pulse
- Temporal to spatial transformation with crossing angle in the EO crystal
- Slippage between bunch field and probe laser field propagating through the crystal
- Wakefield of the bunch interacting with the EO setup

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Electric Field from a Relativistic Bunch

10 μm 33 fs rms

Frequency components $F(\omega) = e \frac{\omega^2 r^2}{2}$

Wakefield bandwidth

$E = 9 \times 10^6 \frac{2N_e e}{r \sqrt{2\pi\sigma_z}} \text{ m.k.s units}$

1 nC 10 μm bunch length

$E = 720 \text{ MV m}^{-1}$ at $r = 1 \text{ μm}$

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Electro Optic detection for ultra-relativistic bunches (very large γ)

+ $1/\gamma$ is very small, so not resolution limited by distance of crystal to beam

+/- very high field strengths

- + easily detectable
- higher-order non-linear Kerr effect is added to the Pockels effect

$E = 9 \times 10^6 \frac{2N_e e}{r \sqrt{2\pi\sigma_z}} \text{ m.k.s units}$

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Electro Optic Basics

$$P = \epsilon_0 [\chi_1 E + \chi_2 E^2 + \chi_3 E^3 + \dots]$$

- Linear, isotropic
- 2nd order, Linear EO Pockels effect
- 3rd order, Quadratic EO Kerr effect

Bandwidth limitation in EO crystals due to optical phonon absorption resonances

6θ, GAPS ~8 THz, GASP ~11 THz

$\chi_1 = n_1^2 - 1$

Is the change in index with approach field

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Electro Optic Probe Geometry

- Probe laser at a crossing angle to electron beam direction
- Probe laser parallel to electron bunch
- Temporal to spatial versus
- Temporal to frequency domain sampling

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Geometry to avoid wakefield perturbation to bunch field

Defocusing aperture M1 EO crystal M2 Probe laser

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Electric field detection

Rms 50 μm

Note: amplitude and profile changes

mirrors

8 nm bunch, 9 nm bunch, 10 nm bunch, 11-15 nm bunch are cut <5% to max.

July 2003 Mainz H. Schlarb

SubPicosecond resolution is lost if we try and extract THz radiation from the vacuum chamber:

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Electric field detection

Check for 50um

exit port mirror beam

H. Schlarb

Electro optic spatial profiling of bunch length distribution

End view

Profile of field operation

Probe laser

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Layout of the 45° EO Crystal Geometry

P. Koepsch

E. Bong

Limits to Resolution

Slippage between bunch field and probe laser field

$$\Delta t = \frac{L}{c} \Delta n$$

for TR and laser

$$= 3 \text{ fs, for } L = 10 \mu\text{m and } \Delta n = 0.1 \text{ in TRs}$$

There is also a transient wavelength shift

$$\frac{\Delta \lambda}{\lambda} = \frac{L}{c} \frac{dn}{dt}$$

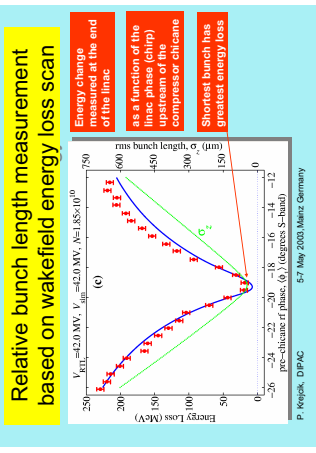
$$= \frac{L}{c} \frac{1}{2} (\omega_p^2 - \omega_{pe}^2)$$

at $V = V_g$

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Relative measurements of the rms bunch length can also be with:

1. Measurement of the wakefield energy loss of the bunch
2. Measurement of the power spectral density of the Coherent Synchrotron Radiation CSR



Aknowledgements

- P. Bolton
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